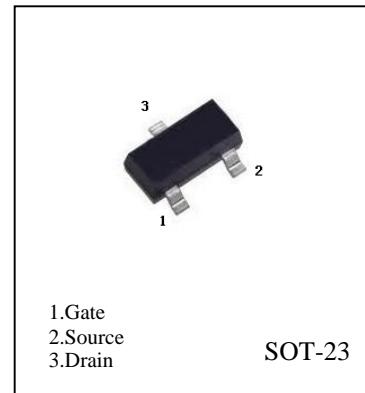


FEATURES

High density cell design for low RDS(ON)
 Voltage controlled small signal switch.
 Rugged and reliable.
 High saturation current capability.

2N7002

N-Channel MOSFET



MAXIMUM RATINGS (TA=25°C unless otherwise noted)

Symbol	Parameter	Ratings	Unit
V _{DS}	Drain-source voltage (V _{GS} = 0)	60	V
V _{DGR}	Drain-gate voltage (R _{GS} = 20 k _Ω)	60	V
V _{GS}	Gate- source voltage	±20	V
I _D	Drain current (continuous) at T _C = 25°C	0.20	A
I _{DM} ⁽¹⁾	Drain current (pulsed)	800	mA
P _{TOT}	Total dissipation at T _C = 25°C	0.35	W
R _{thj- amb}	Thermal resistance junction-ambient max	357.1 ⁽²⁾	°C/W
T _J , T _{tsg}	Operating junction temperature, Storage temperature	- 55 to 150 °C	

ELECTRICAL CHARACTERISTICS (Tamb=25°C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 250μA, V _{GS} = 0	60			V
I _{DSS}	Zero gate voltage drain current (V _{DS} = 0)	V _{DS} = max rating V _{DS} = max rating, T _C =125°C			1 10	μA μA
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ± 18V			±100	nA
V _{GS(th)}	Gate threshold voltage	V _{DS} = V _{GS} , I _D = 250μA	1	2.1	2.5	V
R _{DS(on)}	Static drain-source on resistance	V _{GS} = 10V, I _D = 0.5A V _{GS} = 4.5V, I _D = 0.5A		1.8 2	5 5.3	
g _{fs} ⁽³⁾	Forward transconductance	V _{DS} = 10V , I _D = 0.5A		0.6		S
C _{iss} C _{oss} C _{tss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} = 25V, f = 1MHz, V _{GS} = 0	43 20 6			pF pF pF

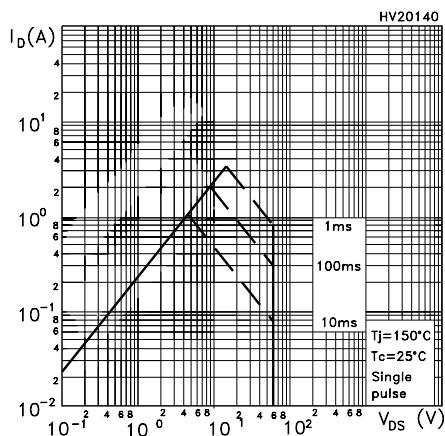
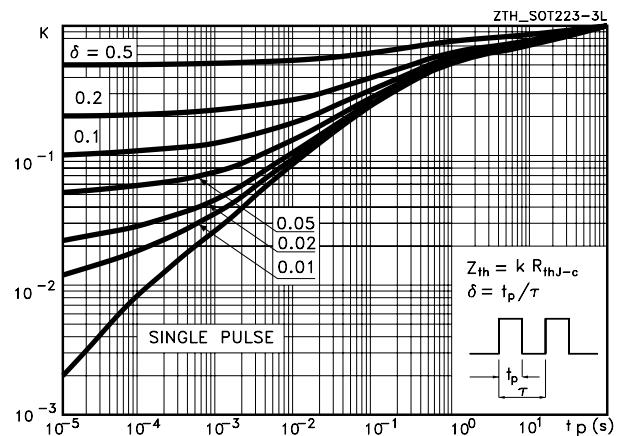
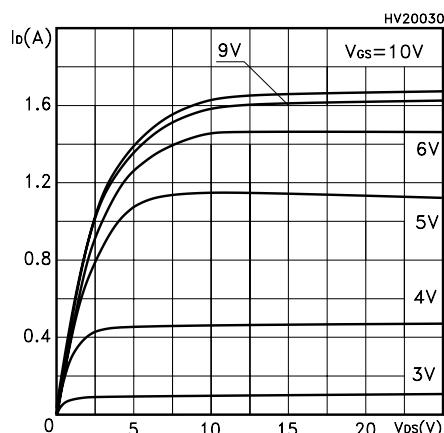
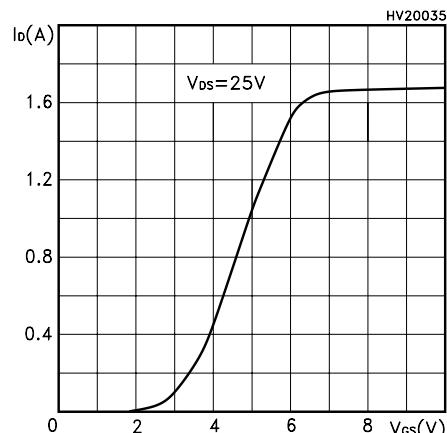
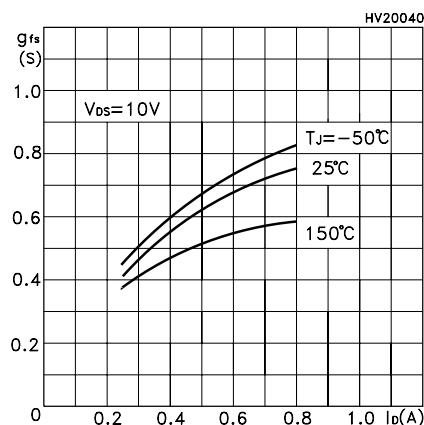
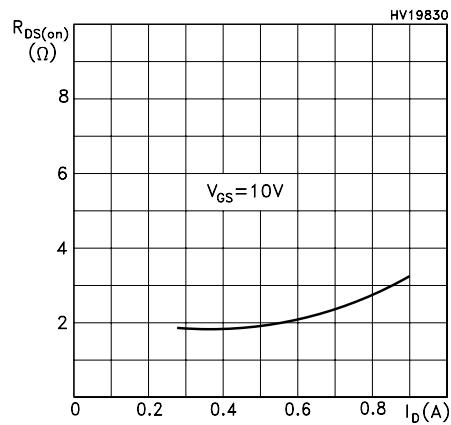
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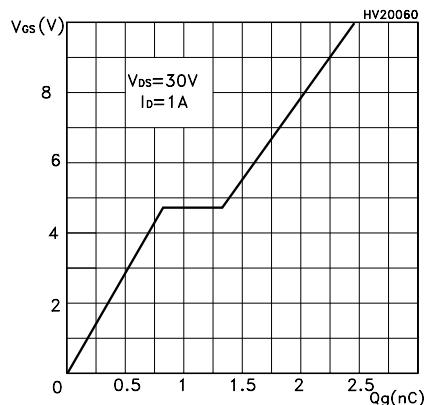
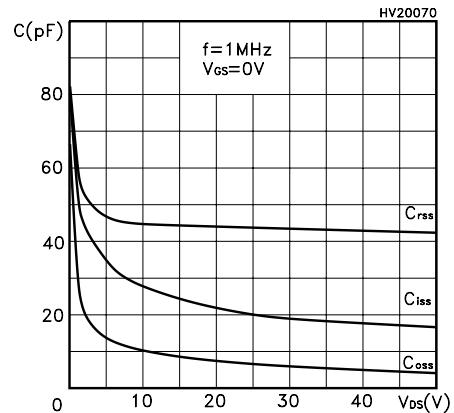
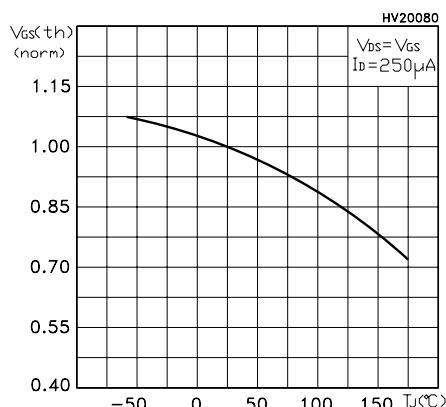
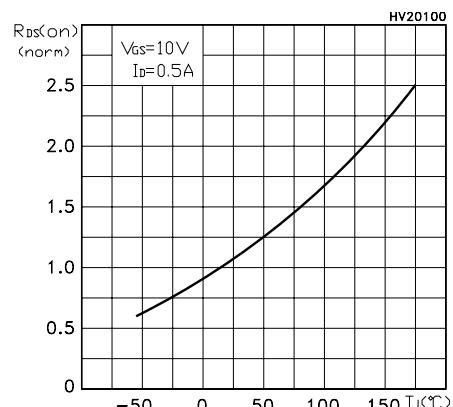
ELECTRICAL CHARACTERISTICS (Tamb=25°C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
t _{d(on)}	Turn-on delay time			5		ns
t _r	Rise time	V = 30V, I = 0.5A		15		ns
t _{d(off)}	Turn-off delay time	R _G = 4.7 V _{GS} = 4.5V		7		ns
t _f	Fall time			8		ns
Q _g	Total gate charge Gate-source charge			1.4		nC
Q _{gs}	Gate-drain charge	V _{DD} = 30V, I _D = 1A, V _{GS} = 5V		0.8	2	nC
Q _{gd}				0.5		nC
I _{SD}	Source-drain current Source-drain				0.35	A
I _{SDM} ⁽⁴⁾	current (pulsed)				1.40	A
V _{SD} ⁽⁵⁾	Forward on voltage	I _{SD} = 1A, V _{GS} = 0			1.2	V
t _{rr} Q _{rr}	Reverse recovery time Reverse recovery			32		ns
I _{RRM}	charge Reverse recovery current	I _{SD} = 1A, di/dt = 100A/μs, V _{DD} = 20V, T _j = 150°C		25		nC
				1.6		A

NOTE: 1. Pulse width limited by safe operating area
 3.Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %.
 5.Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %

2. When mounted on 1inch² FR-4, 2 Oz copper board.
 4.Pulse width limited by safe operating area.

2N7002 Typical Characteristics

Figure 1.Safe operating area

Figure 2.Thermal impedance

Figure 3.Output characteristics

Figure 4.Transfer characteristics

Figure 5.Transconductance

Figure 6.Static drain-source on resistance

2N7002 Typical Characteristics

Figure 7.Gate charge vs gate-source voltage

Figure 8.Capacitance variations

Figure 9.Normalized gate threshold voltage vs temperature

Figure 10.Normalized on resistance vs temperature